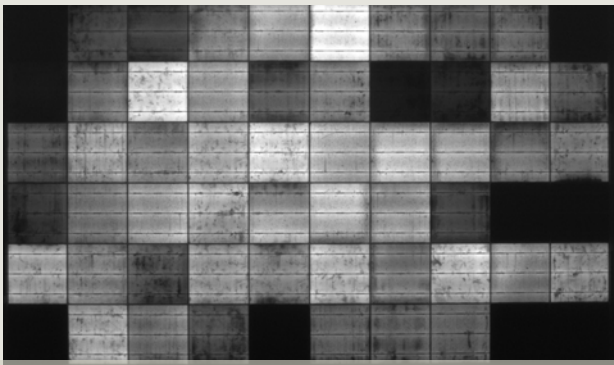
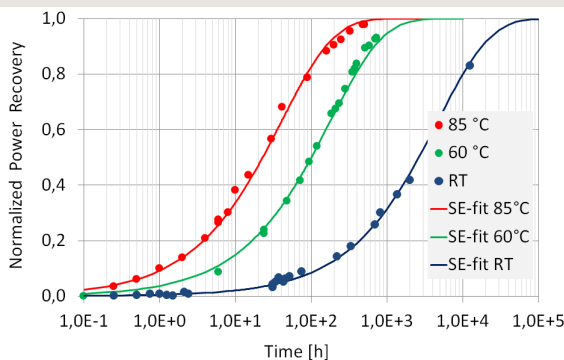


// IR image of PID affected PV modules



// EL image after IEC PID testing



// Recovery behaviour of c-Si modules at different temperatures

PID (Potential Induced Degradation) is a possible risk for the long-term energy yield of any PV installation:

- // PID is still one of the major failure types in the field
- // PID might strike poly and mono c-Si but also thin-film modules
- // The PID effect is prone to a high system voltage and high leakage currents from the module surface into the cells

ZSW provides more than the IEC 62804 laboratory testing:

- // IEC 62804 PID testing and beyond
- // Outdoor performance monitoring of modules under high system voltage
- // Leakage current monitoring
- // PID testing by simulating different climate zones including day/night periods
- // Identify the best recovery strategy after PID problems for each module type:
 - grounding, or
 - positive potential over night, or
 - positive potential during day time
- // Prediction of recovery duration

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